

Status Report for SI to TSG

Study Item Name: Improvement of Inter-frequency and inter-system measurement for 1.28Mcps TDD

SOURCE: Rapporteur

TSG: RAN

WG: WG1

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Ref. to SI sheet: RAN_Study_Items.doc

Progress Report since the last TSG (for all involved WGs):

RAN1:

RAN1#32,

Five contributions [1][2][3][4][5] were submitted for this RAN1 meeting. Reference [1] presented overall considerations for this study item from Siemens point of view. Paper [2] was the reflecting answer from Samsung. After discussion, only the case with 0.8 ms switching time for GSM measurement was agreed to be with potential problem for certain time slot allocation. RAN1 chairman suggested more discussion for this point after this meeting. Paper [3][4][5] addressing further performance impact analysis in the scenario of power control with higher interference difference level and uplink synchronization were skipped because of no full agreement on the problem identification.

RAN2: There is no progress since the last TSG RAN meeting.

RAN3: There is no progress since the last TSG RAN meeting.

RAN4: There is no need of further progress.

List of Completed elements (for complex work items):

RAN1:

Agreement on the study areas of the SI

Completion of the performance evaluation and simulation for the asymmetric time slot allocation pattern to all the possible scenarios with configuration 4 DL, 3 UL time slot.

Completion of the performance evaluation and simulation for the combination of different time slot allocation pattern with configuration 4 DL, 3 UL time slot.

RAN2: Clarification of the SI.

RAN3: Completion of internal skeleton TR for signalling support.

RAN4: Agreement on the impact to the WG4 related specifications

List of open issues:

- Further performance results and analysis on power control impact and uplink synchronization impact for asymmetric pattern and pattern combination schemes.
- More consideration and re-wording for the signalling impact analysis for asymmetric pattern and pattern combination schemes.

Estimates of the level of completion (when possible):

55 %

SI completion date review:

TSG RAN #21 (Sep. 2003)

References to WG's internal documentation and/or TRs:

- [1] 3GPP TSG R1 030424 "Considerations on SI Improvements of Inter-RAT-measurements for 1.28 Mcps TDD", Siemens AG, May. 2003.
- [2] 3GPP TSG R1 030580 "Answer to Siemens' comment on SI Improvements of Inter-RAT-measurements for 1.28Mcps TDD", Samsung Electronics, May. 2003.
- [3] 3GPP TSG R1 030537 "Consideration of interference offset in inter-RAT measurement simulation for 1.28Mcps TDD", Samsung Electronics, May. 2003.
- [4] 3GPP TSG R1 030538 "Text proposal of power control impact for asymmetric pattern and pattern combination scheme", Samsung Electronics, May. 2003.
- [5] 3GPP TSG R1 030539 "Further analysis of asymmetric pattern and pattern combination scheme impact on uplink synchronisation", Samsung Electronics, May. 2003.